

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APR 03 2002

Applicant(s): Han, K. Michael
Assignee: Advanced Micro Devices, Inc.
Title: Recessed Tunnel Oxide Profile For Improved Reliability In NAND
Devices
Serial No.: 09/904,042 Filing Date: July 11, 2001
Examiner: Edward Wojciechowicz Group Art Unit: 2815
Docket No.: M-7468 US

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Newport Beach, California
April 3, 2002

BOX AMENDMENT
COMMISSIONER FOR PATENTS
Washington, D. C. 20231

RESPONSE TO OFFICE ACTION

Dear Sir:

This responds to the Office Action mailed on January 3, 2002. Please amend the above-identified application as follows.

IN THE CLAIMS:

The following is a clean version of the entire set of pending claims. In accordance with 37 C.F.R. § 1.121(c)(1)(ii), Attachment A provides marked up versions of the claims containing the newly introduced changes. Please amend Claims 8, 9 and 10 as follows.

Please cancel Claim 1-7.

Sub B1

8. (Amended) A memory cell comprising:

a semiconductor substrate having a first region and a second region of one conduction type and a third region therebetween of an opposite conduction type;

a gate insulating layer formed over said substrate, the gate insulating layer having a first thickness formed over said first region and said second region, and a second thickness formed over said third region, said first thickness being greater than said second thickness; and

a control gate formed on said gate insulating layer.

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